

Report No.:SZ13070095E01

ANTENNA PERFORMA TEST REP



Issued to

Shenzhen Bopengfa Elec&Technology Co.,Ltd

For

Antenna of Bluetooth Modules

Model Name:

CPR8850F

Trade Name:

RF-LINK

Brand Name:

RDA

Standard:

IEEE149-1979

Test date:

2013-08-07

Issue date:

2013-08-09

by

Shenzhen Morlab Communications Technology Co., Ltd.

Reviewed by

Huang Pulong

2013.8.9

CTIA Authorized Test Lab

IEEE 1725







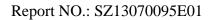


Date



FCC Reg. No. 741109

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1. General Information

1.1 Identification of the Responsible Testing Laboratory

Company Name: Shenzhen Morlab Communications Technology Co., Ltd.

Department: Morlab Laboratory

Address: FL.3, Building A, FeiYang Science Park, No.8 LongChang

Road, Block 67, BaoAn District, ShenZhen, GuangDong

Province, P. R. China 518101

Responsible Test Lab Manager: Mr. Zeng Dexin
Telephone: +86 755 36698555
Facsimile: +86 755 36698525

1.2 Identification of the Responsible Testing Location

Name: Shenzhen Morlab Communications Technology Co., Ltd.

Address: FL.3, Building A, FeiYang Science Park, No.8 LongChang

Road, Block 67, BaoAn District, ShenZhen, GuangDong

Province, P. R. China 518101

1.3 List of Test Equipments

No.	Туре	Specification	
1	8960-5515C System	Manufacturer: Agilent	
1	Simulator		
2	CMU 200 System	Manufacturer: R&S	
2	Simulator		
3	E5071B Vector Network	Manufacturer: Agilent	
3	Analyzer		
4	4*4*4 Full Anechoic	Manufacturer: Satimo	
4	Chamber	Manufacturer. Satinio	
	SG24 Multi-probe		
5	Antenna Measurement	Manufacturer: Satimo	
	System		



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2. Technical Information

Note: Provide by applicant.

Address:

2.1 Applicant Information

Company: Shenzhen Bopengfa Elec&Technology Co.,Ltd

bldg56A,3/F,BaotianRd3,XixiangTown,Baoan,District,

Shenzhen

 Contact:
 Jingyu Chen

 Telephone:
 13923480361

 Fax:
 0755-83704870

E-mail: jingyuchen@rf-link.net

2.2 Antenna under Test (AUT) Description

Brand Name: RDA

Model Name: CPR8850F

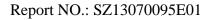
2.2.1 Photographs of the EUT

Please reference annex B.

2.2.2 Identification of all used EUTs

The EUT Identity consists of numerical and letter characters (see the table below), the first five numerical characters indicates the Type of the EUT defined by Morlab, the next letter character indicates the test sample, and the following two numerical characters indicates the software version of the test sample.

EUT Identity	Memo
AUT01	N/A





3. Test Results

3.1 Applied Reference Documents

Leading reference documents for testing:

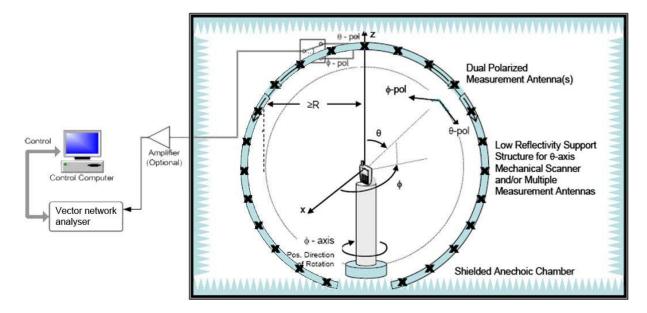
		8	
No.	Identity	Document Title	
1	IEEE149-1979	IEEE Standard Test Procedures for Antennas	

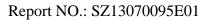
3.2 Test Conditions

Test Environment Conditions:

1) Temperature: 23° C 2) Relative Humidity: 49%

Test Setup:







3.3 Test Results lists

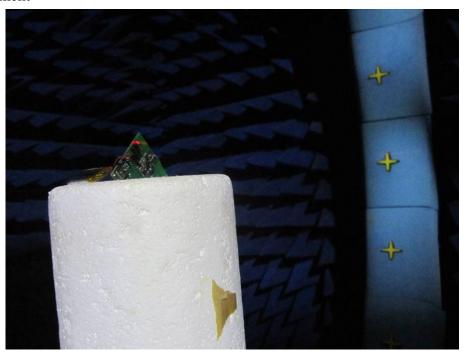
3.3.1 Gain and Efficiency

Frequency	Gain(dBi)	Efficiency
2400MHz	-2.65934	19.32%
2410MHz	-2.49845	20.46%
2420MHz	-2.47123	20.53%
2430MHz	-2.807	19.56%
2440MHz	-2.6876	20.11%
2450MHz	-2.84033	19.63%
2460MHz	-2.84053	20.83%
2470MHz	-2.41596	22.98%
2480MHz	-2.33469	23.12%
2490MHz	-1.93267	24.49%
2500MHz	-1.60768	24.69%

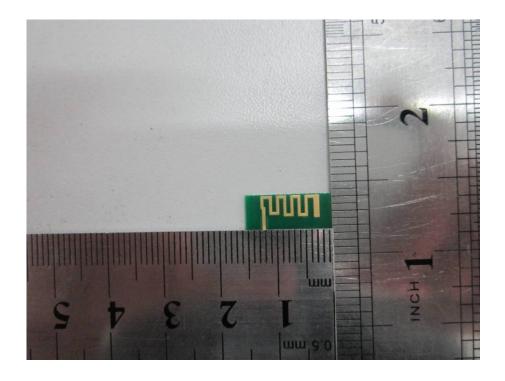


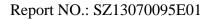
Annex A. Photographs

1. Test environment



2. EUT



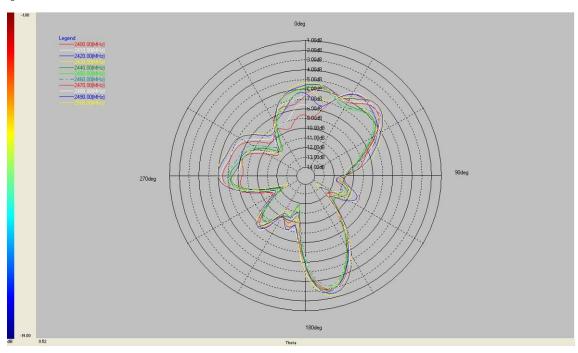




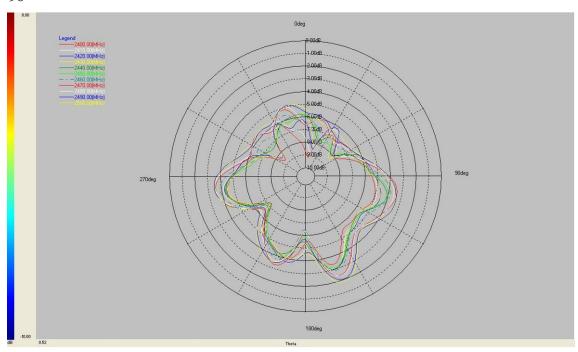
Figures

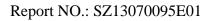
2D Radiation Pattern

1. Phi=0

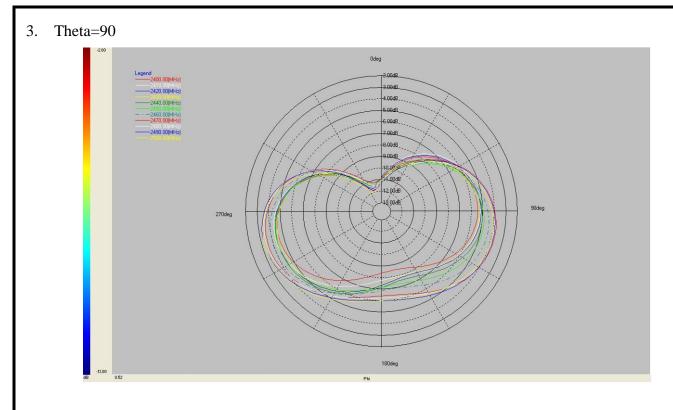


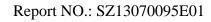
2. Phi=90





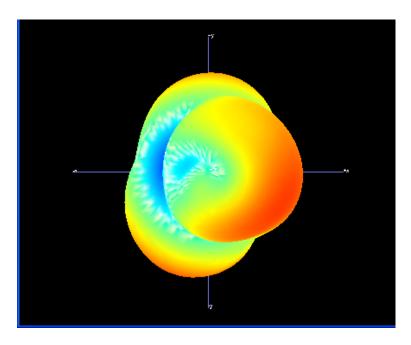




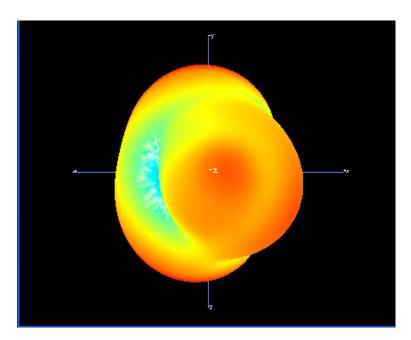




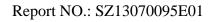
3D Radiation Pattern



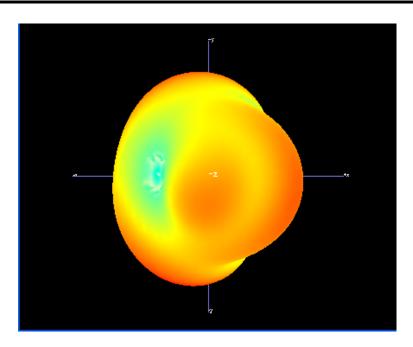
2400MHz



2450MHz







2500 MHz

** END OF REPORT **